

# FI4905-VB Datasheet P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub>	-60	V		
R <sub>DS(on)</sub> V <sub>GS</sub> = 10 V	19	mΩ		
$R_{DS(on)}$ $V_{GS} = 4.5 \text{ V}$	26	mΩ		
I <sub>D</sub>	-50	Α		
Configuration	Single			

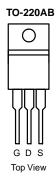
#### **FEATURES**

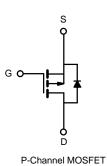
- Trench Power MOSFET
- 100 % UIS Tested

#### **APPLICATIONS**

Load Switch







Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 60	V	
Gate-Source Voltage		$V_{GS}$	± 20		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C		- 50		
	T <sub>C</sub> = 70 °C	, –	- 46		
	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-39	А	
	T <sub>A</sub> = 70 °C		-34		
Pulsed Drain Current		I <sub>DM</sub>	- 200		
Avalanche Current Pulse	1 0411	I <sub>AS</sub>	- 45		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	101	mJ	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	,	69 <sup>a</sup>	^	
	T <sub>A</sub> = 25 °C	I <sub>S</sub>	20 <sup>b</sup>	Α	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		104.2 <sup>a</sup>		
	T <sub>C</sub> = 70 °C	Б	66.7 <sup>a</sup>	147	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>b</sup>	W	
	T <sub>A</sub> = 70 °C		2 <sup>b</sup>	1	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	$R_{thJA}$	33	40	°C/W	
Maximum Junction-to-Case	Steady State	$R_{thJC}$	0.98	1.2		

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 60			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		68		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	1 <sub>D</sub> = - 250 μΛ		- 5.2		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current		V <sub>DS</sub> = - 60 V, V <sub>GS</sub> = 0 V			- 1	μΑ
	I <sub>DSS</sub>	V <sub>DS</sub> = - 60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = - 5 V, V <sub>GS</sub> = - 10 V	- 120			Α
	В	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 30 A		19	<b>+</b>	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 20 A		26		mΩ
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 50 A	20			S
Dynamic <sup>b</sup>				L	L	
Input Capacitance	C <sub>iss</sub>			3700		
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		390		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			290		
		V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 55 A		76 115		
Total Gate Charge	Qg			38	60	nC
Gate-Source Charge	$Q_{gs}$	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 55 A		16		
Gate-Drain Charge	$Q_{gd}$			19		
Gate Resistance	$R_{g}$	f = 1 MHz		5.2		Ω
Turn-On Delay Time	t <sub>d(on)</sub>			10	15	
Rise Time	t <sub>r</sub>	$V_{DD} = -2 \text{ V}, R_L = 2 \Omega$		7	15	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		70	110	ns
Fall Time	t <sub>f</sub>			40	60	1
<b>Drain-Source Body Diode Characteristics</b>	S			l.	l	
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 69	_
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	1			- 150	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 30 A		- 1	- 1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			45	68	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			59	120	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -50 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °C$		29		
Reverse Recovery Rise Time	t <sub>b</sub>			16		ns

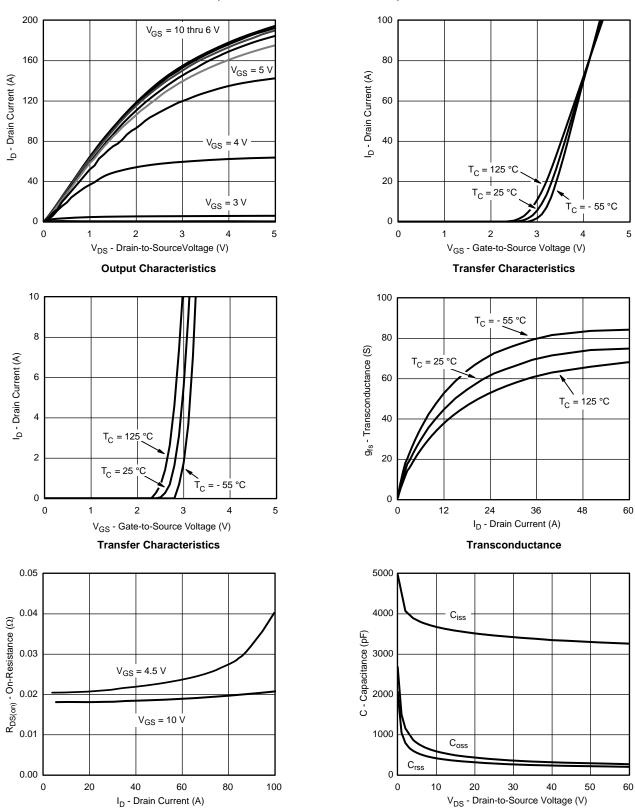
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

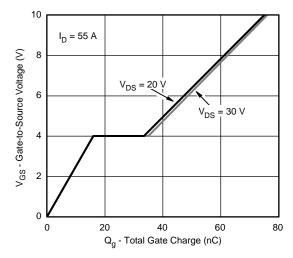


On-Resistance vs. Drain Current

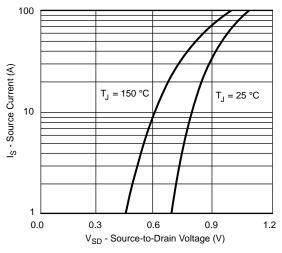
Capacitance



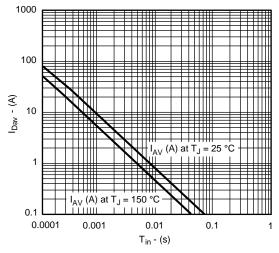
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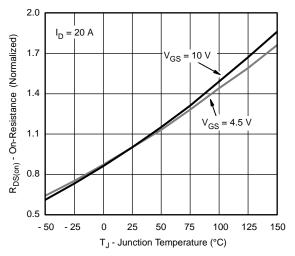
#### **Gate Charge**



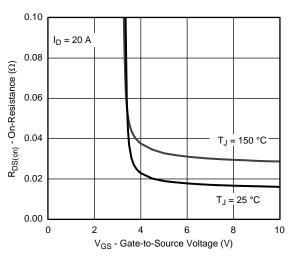
#### Source-Drain Diode Forward Voltage



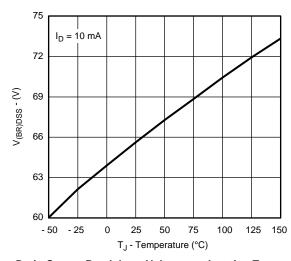
Single Pulse Avalanche Current Capability vs. Time



On-Resistance vs. Gate-to-Source Voltage



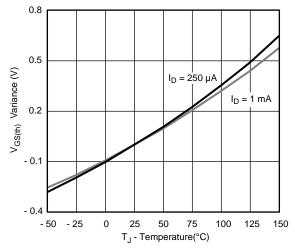
On-Resistance vs. Gate-to-Source Voltage

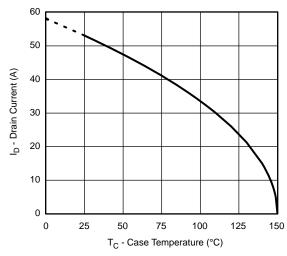


Drain-Source Breakdown Voltage vs. Junction Temperature

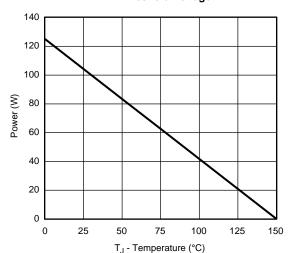


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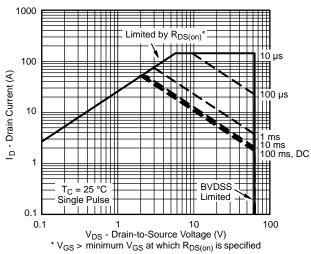




#### Threshold Voltage

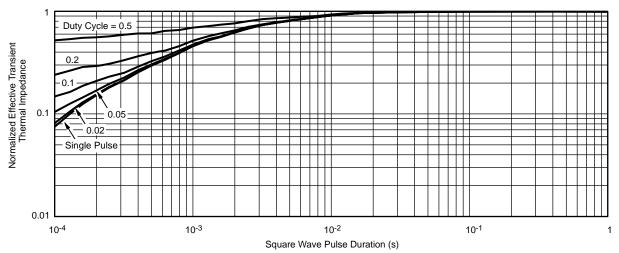


Max. Drain Current vs. Case Temperature



#### Power Derating, Junction-to-Case

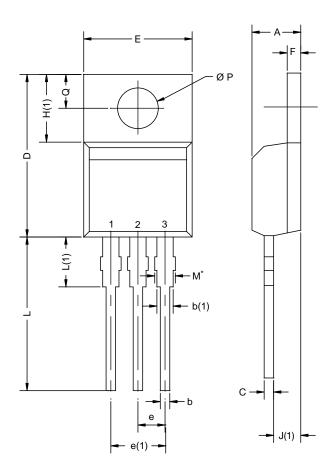




Normalized Thermal Transient Impedance, Junction-to-Case



### **TO-220AB**



	MILLIM	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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